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INFORMATION DISCLOSURE STATEMENT (use several sheets if necessary)				APPLICANT Philip S. Chen, et al.			
				FILING DATE 1/16/2004		GROUP TBA 2856	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	10/273,036		Frank DiMeo, et al.			10/17/2002
	AB	6,265,222	6/24/2001	Frank DiMeo, Jr., et al.			
	AC	5,679,576 A	10/21/1997	Kawai, et al.			
	AD	5,612,489 A	3/18/1997	Ragsdale, et al.			
	AE	6,428,713 B1	8/6/2002	Christenson, et al.			
	AF	4,723,438 A	2/9/1988	Adler-Golden, et al.			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY	CLASS	SUBCLAS S	TRANSLATION YES NO
							X (abstract only)
OTHER DOCUMENTS (Including Author, Title, Journal-Date, Page Number, Etc.)							
	AG	Anderson, B., et al., Semiconductor International, October 1993					
	AH	Ed P. Hagenmuller, Inorganic Solid Fluorides, Chemistry and Physics, Academic Press, 1985. (See Information Disclosure Statement Box 1)					
	AI	W. Moritz, et al., Sensors and Actuators B 24-25 (1995) 194-196, "Monitoring of HF and F2 using a field-effect sensor"					
	AJ	Dr. Shigeru Kurosawa, et al., Fluorine in Coatings II, Paper 33, pgs. 1-8, "Plasma Polymerisation of Fluorine Contained Polycyclic Compounds: Its Application in Chemical Sensors"					
	AK	Werner Moritz, et al., The 11th European Conference on Solid State Transducers, Warsaw, Poland, pgs. 111-114, September 21-24, 1997, "Gas Sensors for Fluorine Using Different Semiconductor Substrates"					
	AL	Semiconductor International, "Residual Gas Analysis", Oct. 1997, pgs. 94-100					
	AM	W. Moritz, et al., "Silicon-Based Sensor for Fluorine Gas", American Chemical Society, pgs. 119-129.					
	Continue on Page						
EXAMINER 					DATE CONSIDERED 09/18/05		
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.							